

<b>Notice of References Cited</b>	Application/Control No. 10/631,330	Applicant(s)/Patent Under Reexamination DEMEL ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-3,627,338	12-1971	Thompson, Sheldon	279/3
	B	US-4,131,267	12-1978	Ono et al.	269/21
	C	US-5,191,218	03-1993	Mori et al.	250/453.11
	D	US-5,324,012	06-1994	Aoyama et al.	269/21
	E	US-5,989,760	11-1999	Mangat et al.	430/22
	F	US-6,072,157	06-2000	Klebanoff et al.	219/228
	G	US-6,271,676	08-2001	Montoya, Thomas T.	324/765
	H	US-6,375,176	04-2002	Getchel et al.	269/21
	I	US-6,386,957	05-2002	Masumura et al.	451/59
	J	US-6,540,014	04-2003	Getchel et al.	165/80.1
	K	US-6,632,325	10-2003	Lingampalli, Ramkishan Rao	156/345.51
	L	US-6,402,594	06-2002	Kobayashi et al.	451/41
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	GB 2149697 A	06-1985	United Kingdom	NEUKERMANS et al.	B25B 11/00
	O	JP 05082631 A	04-1993	Japan	TAKEMURA, FUMIHIRO	H01L 21/68
	P	JP 05047909 A	02-1993	Japan	NAKATSUI, HISASHI	H01L 21/68
	Q	JP 03286549 A	12-1991	Japan	WATANABE et al.	H01L 21/68
	R	JP 64001294 A	01-1989	Japan	KUNI et al.	H05K 03/00
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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